

# Advanced Topics in VLSI EE-6361

## Probability Tutorial

February 9, 2017

1. Suppose five fair coins are tossed. Let E be the event that three coins show heads. Define the indicator random variable  $I_E$  to be 1 if E occurs and 0 otherwise. For what outcomes in the original sample space does  $I_E$  equal to 1? What is the value of  $P(\{I_E = 1\})$ . What is the mean and variance of  $I_E$ ?

$$I_E = \begin{cases} 1 & \text{if E occurs} \\ 0 & \text{otherwise} \end{cases}$$

2. Let  $I_\alpha$  be an indicator RV that indicates that a value drawn from a Standard Normal distribution is  $\geq \alpha$ . Calculate  $E[I_\alpha]$  for (a)  $\alpha = 0$  (b)  $\alpha = 0.75$  and (c)  $\alpha = -0.75$
3. A geometric RV,  $X$ , is an integer valued RV ( $\geq 1$ ) and is defined to be the number flips of a coin required to get a head. Assume that the coin shows a head with probability  $p$ . Find the probability mass function  $P(\{X = n\})$  for  $n \geq 1$ .
4. A binomial RV,  $X$ , is an integer valued RV ( $\geq 0$ ) that represents the number of successes of a Bernoulli RV in  $n$  trials. If  $p$  represents the probability of success of the Bernoulli RV, find the following
  - Probability mass function  $P(\{X = k\})$  for  $k \geq 0$ ,
  - Mean of  $X$
  - Variance of  $X$
5. A coin having probability  $p$  of coming up heads is successively flipped until the  $r^{th}$  head appears. Show that the random variable  $X$ , number of flips required, will be  $n \geq r$ , is defined by the probability mass function

$$P(\{X = n\}) = \binom{n-1}{r-1} p^r (1-p)^{n-r} \dots n \geq r$$

6. Consider a memory with  $N$  cells that has a row redundancy fix of up to  $K$  rows. Assume that each cell can fail with a probability  $p$ . Calculate the probability of failure of the whole memory.

7. Let  $X_1, X_2 \dots X_n$  be iid uniform RV over  $[0, 1]$ . Find the CDF of  $M = \max(X_1, X_2 \dots X_n)$

8. Let  $c$  be a constant. Show that

$$\text{Var}(cX) = c^2 \text{Var}(X)$$

$$\text{Var}(c + X) = \text{var}(X)$$

9. If  $X$  is a Gaussian RV with mean  $\mu$  and standard deviation  $\sigma$ , show that the moment generating function(MGF) is given by

$$E[e^{sX}] = e^{s\mu + \frac{s^2\sigma^2}{2}}$$

10. Use the MGF of a Gaussian RV from above and show that a linear sum of  $n$  independent Gaussian RVs is also Gaussian.

11. The normalized delay of an inverter is given by

$$D = D_{NOM} + 0.3\Delta L + 0.4\Delta V_{TH} \quad (1)$$

Where  $\Delta L$  and  $\Delta V_{TH}$  are normalized delay variations. Assume that in a particular technology,  $D_{NOM} = 30$ ,  $\Delta L$  and  $\Delta V_{TH}$  are standard normal random variables. Calculate the fraction of inverters which have delays greater than 31.5. (This is called performance yield)

12. The leakage of an inverter is given by

$$I_{SUB} = I_0 e^{(-0.3\Delta L - 0.4\Delta V_{TH})}$$

Where  $\Delta L$  and  $\Delta V_{TH}$  are normalized delay variations. Assume that in a particular technology,  $I_{NOM} = 100pA$ ,  $\Delta L$  and  $\Delta V_{TH}$  are standard normal random variables. Calculate the fraction of chips that leak more than  $271.8pA$ . (This is called leakage yield)

13. Use the MGF to prove central limit theorem(CLT) for iid RVs.

14. Let  $Y = \sum_{i=1}^n \alpha_i X_i$  where  $X_i$ 's are independent RVs with mean  $\mu_i$  and standard deviation  $\sigma_i$ . Derive an expression for the mean and standard deviation of  $Y$ .

15. Sample mean of a random variable  $X$  is defined to be  $S_N = \frac{1}{N} \sum_{i=1}^N X_i$  where  $X_i$ 's are iid realizations of  $X$ . Compute the mean and variance of  $S_N$ . What is the distribution of  $S_N$ ? For what value of  $N$  will  $S_N$  be equal to the actual mean  $\mu$ ?

16. Let  $Z$  be a standard normal variable (zero mean and unit variance). If  $\{P(Z > z_\alpha)\} = \alpha$ , show that  $P(\{\frac{\sqrt{N}}{\sigma}(S_N - \mu)\} \leq z_{\frac{\alpha}{2}}) = 1 - \alpha$ . The interval  $\mu \pm \frac{z_{\frac{\alpha}{2}} \sigma}{\sqrt{N}}$  is called the  $100(1 - \alpha)$  percent confidence estimator of the sample mean. Here  $S_N$  is as defined in the previous problem

## Simulation

1. The delay in Equation ( 1) can be written as

$$D = 30 + 0.5X$$

where  $X$  is a standard normal random variable. In MATLAB/ OCTAVE use the “randn” function to generate  $N$  samples of  $X$ .  $P(D > \alpha)$  can be evaluated as the fraction of values of  $D$  that exceed  $\alpha$ . Now evaluate the following by varying  $N$  from  $10^3$  to  $10^7$  in geometrically progressing steps of  $2X$

- $P(D > 30.5)$
- $P(D > 31.5)$
- $P(D > 32)$

Repeat the experiment five times and plot the above probabilities vs  $N$ . What do you observe?

2. Use the theory of importance sampling and show how you can reduce the required number of samples. What’s the new PDF that you constructed?